

Poster Presentation

[OLEDp1]OLED poster

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[OLEDp1-7]A Study of Encapsulation Structure for TFT Reliability in Top Emission OLED Display

*Jae Young Oh¹, Seung Hee Nam¹, Kwon-Shik Park¹, SooYoung Yoon¹, InByeong Kang¹, Jae Kyeong Jeong² (1. LG Display (Korea), 2. Hanyang University (Korea))

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Preventing hydrogen and water vapor from permeating through encapsulation layer plays an important role in TFT Reliability. To improve a blocking characteristic, encapsulation inorganic layers were studied. A SiN_x and SiO₂ multilayered inorganic deposition method for OLED has been developed to obtain a reliable performance.